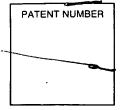
 -	
Subclass	ISSUE CLASSIFICATION
Class	ISSUE CLA

BEST AVAILABLE COPY



U.S. UTILITY Patent Application

o.o. otterri i atont Applio	O.I.P.E. PATENT DATE				
O.I.P.E.	PATENT DATE				
SCANNED KG 4 Q.A. AM					

APPLICATION NO. CONT/PRIOR CLASS SUBCLASS ART UNIT EXAMINER 09/870736 250 Mouraga

Yoshiro Shiokawa Megumi Nakamura Tohru Sasaki Toshihiro Fujii

Method and apparatus for ion attachment mass spectrometry

North ! SMILE A

Γ	ISSUING CLASSIFICATION													
Γ	ORIGINAL						CROSS REFERENCE(S)							
	CLASS SUBCLASS			CLASS		SUBCLASS (ONE SUBCLASS PER BLOCK)								
	INTERNATIONAL CLASSIFICATION								-					
	Τ						i,		-	1				
Γ		Τ				المعتدية الما								
Г	T	T	Π	Γ			·							
	Т												=	
Γ	Т		Γ				1				Continued of	on Issue Slip	Inside File J	acket

Charte Dave			CLAIN	CLAIMS ALLOWED		
Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.		
		1	NOTICE OF ALLOWANCE MAILED			
(Assistant	Examiner)	(Date)				
	-					
			ISSUE FEE			
			Amount Due	Date Paid		
(Primary	Examiner)	(Date)				
			ISSUE BATCH NUMBER			
(Legal Instrum	ents Examiner)	(Date)				
estricted. Unauthorized	disclosure may be	prohibited by the U	United States Code Title 3	5, Sections 122, 181 and 36		
	(Primary in the control of the contr	(Primary Examiner) (Legal Instruments Examiner)	(Primary Examiner) (Date) (Legal Instruments Examiner) (Date) estricted. Unauthorized disclosure may be prohibited by the Umark Office is restricted to authorized employees and contract	(Assistant Examiner) (Date) ISSI Amount Due (Primary Examiner) (Date) ISSUE BAT		

(Attached in pocket on right inside flap)